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sX mapping system test at ORNL

Tuesday 9 July 2024 10:00 (20 minutes)

The Kyoto-KEK sX mapping system was applied to the vertical testing of a 805 MHz 6-cell SNS high-beta cavity (HB60) aimed at localizing field emitters in the cavity. The test result will be presented and implication to the on-going effort in the battle against field emission in current and future SRF cavities will be discussed.

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Session Classification: Superconducting RF

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